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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6128747	10-2000	Thoulon, Pierre-Yves	713/330
	В	US-6112306	08-2000	Volk, Andrew M. et al.	713/323
	С	US-5721937	02-1998	Kurihara, Steven M. et al.	713/323
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
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FOREIGN PATENT DOCUMENTS

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